Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/773,214	WECK ET AL.
Examiner	Art Unit
John Q. Nguyen	3654

SEARCHED			
Class	Subclass	Date	Examiner
242	406 597.5 597.7 597.8	8/19/2005	JN
137	355.16	8/19/2005	JN
137	355.28	8/19/2005	JN
52	155	8/22/2005	JN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
consulted exr. Yip (cl 52)	8/22/2005	NL
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